

TEST REPORT

Application No.: SZCR2407002522AT
Applicant: Baicells Technologies Co., Ltd.
Address of Applicant: 9-10F, 1st Bldg., No. 81 Beiqing Road, Haidian District, Beijing, China
Manufacturer: Baicells Technologies Co., Ltd.
Address of Manufacturer: 9-10F, 1st Bldg., No. 81 Beiqing Road, Haidian District, Beijing, China
Equipment Under Test (EUT):
EUT Name: 5G Outdoor CPE
Model No.: EG8561A-NR11
Trade Mark: Baicells
FCC ID: 2AG32EG8561ANR11
Standards: 47 CFR Part 2
47 CFR Part 96
Date of Receipt: 2024-07-01
Date of Test: 2024-08-06 to 2024-09-12
Date of Issue: 2024-09-18

Test Result :	PASS *
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* In the configuration tested, the EUT detailed in this report complied with the standards specified above.

Keny Xu

Keny Xu
EMC Laboratory Manager



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SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

SZEMC-TRF-01 Rev. A/1

Report No.: SZCR240700252202

Page: 2 of 28

Revision Record				
Version	Chapter	Date	Modifier	Remark
01		2024-09-18		Original

Authorized for issue by:				
		Frank Chen		
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		Eric Fu		
		Eric Fu/Reviewer		



SGS-CSTC Standards Technical Services Co., Ltd.
Shenzhen Branch (SGS-CSTC) Laboratory

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Contents

1	Test Summary	4
1.1	LTE Band 48/ LTE CA_48C	4
2	General Information	6
2.1	Details of E.U.T.	6
2.2	Technical Specification	7
2.3	Test Frequencies	8
2.4	Test Mode	10
2.5	Test Environment	10
2.6	Description of Support Units	10
2.7	Test Location	11
2.8	Test Facility	11
3	Description of Tests	12
3.1	Conducted Output Power	12
3.2	Effective (Isotropic) Radiated Power of Transmitter	13
3.3	Occupied Bandwidth	14
3.4	Band Edge at Antenna Terminals	15
3.5	Spurious And Harmonic Emissions at Antenna Terminal	16
3.6	Peak-Average Ratio	17
3.7	Field Strength of Spurious Radiation	18
3.8	Frequency Stability / Temperature Variation	20
3.9	Test Setups	21
3.9.1	Test Setup 1	21
3.9.2	Test Setup 2	21
3.9.3	Test Setup 3	22
3.10	Test Conditions	23
4	Main Test Instruments	25
5	Measurement Uncertainty	27
6	Appendixes	28



1 Test Summary

1.1 LTE Band 48/ LTE CA_48C

Test Item	FCC Rule No.	Requirements	Test Result	Verdict
Effective (Isotropic) Radiated Power Output Data	§2.1046, §96.41	EIRP \leq 23dBm/10MHz	Section 1 of Appendix B.1 & B.2	Pass
Peak-Average Ratio	§96.41	FCC: Limit \leq 13 dB	Section 2 of Appendix B.1 & B.2	Pass
Bandwidth	§2.1049	OBW: No limit. EBW: No limit.	Section 3 of Appendix B.1 & B.2	Pass
Adjacent Channel Leakage Ratio	§96.41	the Adjacent Channel Leakage Ratio for End User Devices shall be at least 30 dB.	Section 4 of Appendix B.1 & B.2	Pass
Band Edges Compliance	§2.1051, §96.41	for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed -13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge.	Section 5 of Appendix B.1 & B.2	Pass
Spurious Emission at Antenna Terminals	§2.1051, §96.41	for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed -13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge. At all frequencies greater than B megahertz above the upper CBSD assigned channel edge and less than B megahertz below the lower CBSD-assigned channel edge, the conducted power of any End User Device emission shall not	Section 6 of Appendix B.1 & B.2	Pass



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		<p>exceed -25 dBm/MHz.</p> <p>(2) Additional protection levels.</p> <p>Notwithstanding paragraph (e)(1) of this section, for CBSDs and End User Devices, the conducted power of emissions below 3540 MHz or above 3710 MHz shall not exceed -25 dBm/MHz, and the conducted power of emissions below 3530 MHz or above 3720 MHz shall not exceed -40dBm/MHz.</p>		
Field Strength of Spurious Radiation	\$2.1053, \$96.41	<p>for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed -13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge. At all frequencies greater than B megahertz above the upper CBSD assigned channel edge and less than B megahertz below the lower CBSD-assigned channel edge, the conducted power of any End User Device emission shall not exceed -25 dBm/MHz.</p> <p>(2) Additional protection levels.</p> <p>Notwithstanding paragraph (e)(1) of this section, for CBSDs and End User Devices, the conducted power of emissions below 3540 MHz or above 3710 MHz shall not exceed -25 dBm/MHz, and the conducted power of emissions below 3530 MHz or above 3720 MHz shall not exceed -40dBm/MHz.</p>	Section 7 of Appendix B.1 & B.2	Pass
Frequency Stability	\$2.1055, \$96.41	Within authorized bands of operation/ frequency block.	Section 8 of Appendix B.1 & B.2	Pass



2 General Information

2.1 Details of E.U.T.

Power supply:	POE POWER SUPPLY Model: G0720-240-100 Input Power: AC 100-240V 50-60Hz 0.75A Max DC Output: 24V 1A		
Sample Type:	Fixed production		
Hardware Version:	VER.B		
Software Version:	BaiCE_BQ_1.2.16.28_NA		
Antenna Type:	Directional Antenna		
Antenna Gain*:	<input checked="" type="checkbox"/> Provided by client		
	LTE Band 48: 14dBi(Ant1)		
RF Cable:	0.8dB(Below 1GHz)	1.0dB(1.0~2.4GHz)	1.2dB(2.4~3.4GHz)
	1.5dB(Above 3.4GHz)	/	/
<p>Note: *Since the above data and/or information is provided by the client relevant results or conclusions of this report are only made for these data and/or information , SGS is not responsible for the authenticity, integrity and results of the data and information and/or the validity of the conclusion.</p> <p>Remark: As above information is provided and confirmed by the applicant. SGS is not liable to the accuracy, suitability, reliability or/and integrity of the information.</p>			



2.2 Technical Specification

Characteristics	Description					
Radio System Type	<input checked="" type="checkbox"/> LTE					
Supported Frequency Range	Band	TX			RX	
	LTE Band 48	3550 to 3700 MHz			3550 to 3700 MHz	
	LTE CA_48C	3550 to 3700 MHz			3550 to 3700 MHz	
	LTE Band 48	<input checked="" type="checkbox"/> 5 MHz	<input checked="" type="checkbox"/> 10 MHz	<input checked="" type="checkbox"/> 15 MHz	<input checked="" type="checkbox"/> 20 MHz	
	LTE Band CA_48C	<input checked="" type="checkbox"/> 10MHz+20MHz		<input checked="" type="checkbox"/> 15MHz+20MHz		
		<input checked="" type="checkbox"/> 20MHz+10MHz		<input checked="" type="checkbox"/> 20MHz+15MHz		
		<input checked="" type="checkbox"/> 20MHz+20MHz		<input checked="" type="checkbox"/> 20MHz+5MHz		
		<input checked="" type="checkbox"/> 5MHz+20MHz				
Note: only the worst case was tested and the data displayed in this report.						
Designation of Emissions (Remark: the necessary bandwidth of which is the worst value from the measured occupied bandwidths for each type of channel bandwidth configuration.)	E-UTRA:	QPSK	16QAM	64QAM	256QAM	
	LTE Band 48	4M50G7D	4M51W7D	4M50W7D	4M51W7D	
		9M02G7D	8M99W7D	9M02W7D	8M99W7D	
		13M6G7D	13M5W7D	13M5W7D	13M5W7D	
		18M2G7D	18M1W7D	18M0W7D	18M1W7D	
	LTE Band CA_48C	50RB+100RB:				
		27M8G7D	27M7W7D	27M6W7D	27M6W7D	
		75RB+100RB:				
		32M7G7D	32M6W7D	32M5W7D	32M5W7D	
		100RB+50RB:				
		27M8G7D	27M8W7D	27M7W7D	27M8W7D	
		100RB+75RB:				
		32M7G7D	32M7W7D	32M5W7D	32M6W7D	
		100RB+100RB:				
		37M9G7D	37M7W7D	37M7W7D	37M7W7D	
		100RB+25RB:				
		23M0G7D	23M0W7D	22M9W7D	23M0W7D	
25RB+100RB:						
23M0G7D	22M9W7D	22M8W7D	22M8W7D			



2.3 Test Frequencies

Test Mode	Bandwidth	TX / RX	RF Channel		
			Low (L)	Middle (M)	High (H)
LTE Band 48	5MHz	TX/RX	Channel 55265	Channel55990	Channel 56715
			3552.5 MHz	3625.0 MHz	3697.5 MHz
	10MHz	TX/RX	Channel 55290	Channel55990	Channel 56690
			3555.0 MHz	3625.0 MHz	3695.0 MHz
	15MHz	TX/RX	Channel 55315	Channel55990	Channel 56665
			3557.5 MHz	3625.0 MHz	3692.5 MHz
	20MHz	TX/RX	Channel 55340	Channel55990	Channel 56640
			3560.0 MHz	3625.0 MHz	3690.0 MHz



Table 4.3.1.2.16A-1: Test frequencies for CA_48C

Range	CC-Combo / N _{RB_agg} [RB]	CC1 Note1			CC2 Note1		
		BW [RB]	N _{UL/DL}	f _{UL/DL} [MHz]	BW [RB]	N _{UL/DL}	f _{UL/DL} [MHz]
Low	25+100	25	55273	3553.3	100	55390	3565
		100	55340	3560	25	55457	3571.7
	50+100	50	55295	3555.5	100	55439	3569.9
		100	55340	3560	50	55484	3574.4
	75+100	75	55318	3557.8	100	55489	3574.9
		100	55340	3560	75	55511	3577.1
Mid	25+100	25	55898	3615.8	100	56015	3627.5
		100	55965	3622.5	25	56082	3634.2
	50+100	50	55896	3615.6	100	56040	3630
		100	55941	3620.1	50	56085	3634.5
	75+100	75	55893	3615.3	100	56064	3632.4
		100	55916	3617.6	75	56087	3634.7
High	25+100	25	56523	3678.3	100	56640	3690
		100	56590	3685	25	56707	3696.7
	50+100	50	56496	3675.6	100	56640	3690
		100	56541	3680.1	50	56685	3694.5
	75+100	75	56469	3672.9	100	56640	3690
		100	56491	3675.1	75	56662	3692.2
High	100+100	100	56442	3670.2	100	56640	3690

Note 1: Carriers in increasing frequency order.



2.4 Test Mode

Test Mode	Test Modes Description
LTE/TM1	LTE system, QPSK modulation
LTE/TM2	LTE system, 16QAM modulation
LTE/TM3	LTE system, 64QAM modulation
LTE/TM4	LTE system, 256QAM modulation
Remark: The test mode(s) are selected according to relevant radio technology specifications.	

2.5 Test Environment

Environment Parameter	101 kPa Selected Values During Tests	
Relative Humidity	50-55 % RH Ambient	
Value	Temperature(°C)	Voltage(V)
NTNV	22~23	24
LTLV	-30	22.8
LTHV	-30	25.2
HTLV	50	22.8
HTHV	50	25.2
Remark:		
NV: Normal Voltage	LV: Low Extreme Test Voltage	HV: High Extreme Test Voltage
NT: Normal Temperature	LT: Low Extreme Test Temperature	HT: High Extreme Test Temperature

2.6 Description of Support Units

The EUT has been tested as an independent unit.



2.7 Test Location

Company:	SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch
Address:	No. 1 Workshop, M-10, Middle section, Science & Technology Park, Nanshan District, Shenzhen, Guangdong, China
Post code:	518057

2.8 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

• A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

• VCCI

The 3m Fully-anechoic chamber for above 1GHz, 10m Semi-anechoic chamber for below 1GHz, Shielded Room for Mains Port Conducted Interference Measurement and Telecommunication Port Conducted Interference Measurement of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-20026, R-14188, C-12383 and T-11153 respectively.

• Innovation, Science and Economic Development Canada

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch has been recognized by ISED as an accredited testing laboratory.

CAB identifier: CN0006.

IC#: 4620C.

• FCC –Designation Number: CN1336

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch has been recognized as an accredited testing laboratory.

Designation Number: CN1336.

Test Firm Registration Number: 787754



3 Description of Tests

3.1 Conducted Output Power

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.2.1

The transmitter output was connected to a calibrated coaxial cable, attenuator and power meter, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The power output at the transmitter antenna port was determined by adding the value of the cable insertion loss to the power reading. The tests were performed at three frequencies (low channel, middle channel and high channel) and on the highest power levels, which can be setup on the transmitters.

Remark: Reference test setup 1



3.2 Effective (Isotropic) Radiated Power of Transmitter

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.8.4

Calculate power in dBm by the following formula:

ERP (dBm) = Conducted Power (dBm) + antenna gain (dBd)

EIRP(dBm) = Conducted Power (dBm) + antenna gain (dBi)

EIRP=ERP+2.15dB



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3.3 Occupied Bandwidth

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 4.2 & 4.3

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel, middle channel and high channel). The span of the analyzer shall be set to capture all products of the modulation process, including the emission skirts. The resolution bandwidth shall be set to as close to 1 percent of the selected span as is possible without being below 1 percent. The video bandwidth shall be set to 3 times the resolution bandwidth. Video averaging is not permitted. Where practical, a sampling detector shall be used since a peak or, peak hold, may produce a wider bandwidth than actual. The trace data points are recovered and are directly summed in linear terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5 percent of the total is reached and that frequency recorded. The process is repeated for the highest frequency data points. This frequency is recorded. The span between the two recorded frequencies is the occupied bandwidth.

Remark: Reference test setup 1

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW $\geq 3 \times$ RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7



3.4 Band Edge at Antenna Terminals

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 6.0

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at two frequencies (low channel and high channel).in the 1MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of 100kHz or 1% of the emission bandwidth of the fundamental emission of the transmitter may be employed. The EUT emission bandwidth is measured as the width of the signal between two points, outside of which all emission are attenuated at least 26dB below the transmitter power. The video bandwidth of the spectrum analyzer was set at thrice the resolution bandwidth. Detector Mode was set to rms.

Remark: Reference test setup 1

Test Settings

1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
2. Span was set large enough so as to capture all out of band emissions near the band edge
3. RBW \geq 1% of the emission bandwidth
4. VBW \geq 3 x RBW
5. Detector = RMS
6. Number of sweep points \geq 2 x Span/RBW
7. Trace mode = trace average for continuous emissions, max hold for pulse emissions
8. Sweep time = auto couple
9. The trace was allowed to stabilize



3.5 Spurious And Harmonic Emissions at Antenna Terminal

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 6.0

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyzer, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel and high channel). The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. On any frequency outside a licensee's frequency block, the power of any emission shall be attenuated below the transmitter power (P) by at least $43 + 10 \log(P)$ dB. Compliance with these provisions is based on the use of measurement instrumentation employing a resolution bandwidth of 1 MHz or greater. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

Remark: Reference test setup 1

Test Settings

1. Start frequency was set to 9kHz and stop frequency was set to at least 10* the fundamental frequency (Separated into at least two plots per channel)
2. Detector = RMS
3. Trace mode = trace average for continuous emissions, max hold for pulse emissions
4. Sweep time = auto couple
5. The trace was allowed to stabilize
6. Please see test notes below for RBW and VBW settings



3.6 Peak-Average Ratio

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.7.2

A peak to average ratio measurement is performed at the conducted port of the EUT. For WCDMA signals, the spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level. For GSM signals, an average and a peak trace are used on a spectrum analyzer to determine the largest deviation between the average and the peak power of the EUT in a bandwidth greater than the emission bandwidth. The traces are generated with the spectrum analyzer set to zero span mode.

Remark: Reference test setup 1

Test Settings

1. The signal analyzer's CCDF measurement profile is enabled
2. Frequency = carrier center frequency
3. Measurement BW > Emission bandwidth of signal
4. The signal analyzer was set to collect one million samples to generate the CCDF curve
5. The measurement interval was set depending on the type of signal analyzed. For continuous signals (>98% duty cycle), the measurement interval was set to 1ms. For burst transmissions, the spectrum analyzer is set to use an internal "RF Burst" trigger that is synced with an incoming pulse and the measurement interval is set to less than the duration of the "on time" of one burst to ensure that energy is only captured during a time in which the transmitter is operating at maximum power



3.7 Field Strength of Spurious Radiation

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.8

Below 1GHz test procedure as below:

- 1). The EUT was powered ON and placed on a 80cm high table in the chamber. The antenna of the transmitter was extended to its maximum length.
- 2). The disturbance of the transmitter was maximized on the test receiver display by raising and lowering from 1m to 4m (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) the receive antenna and by rotating through 360° the turntable. After the fundamental emission was maximized, a field strength measurement was made.
- 3). Steps 1) and 2) were performed with the EUT and the receive antenna in both vertical and horizontal polarization.
- 4). Test the EUT in the lowest channel, the middle channel ,the Highest channel.
- 5). The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 6). Repeat above procedures until all frequencies measured was complete.

$$E \text{ (dB}\mu\text{V/m)} = \text{Measured amplitude level (dB}\mu\text{V)} + (\text{Cable Loss (dB)} + \text{Antenna Factor (dB/m)} - \text{AMP(dB)})$$

$$\text{EIRP (dBm)} = E \text{ (dB}\mu\text{V/m)} + 20 \log D - 104.8; \text{ where D is the measurement distance in meters}$$

Above 1GHz test procedure as below:

- 1) Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber
- 2) Calculate power in dBm by the following formula:

$$E \text{ (dB}\mu\text{V/m)} = \text{Measured amplitude level (dB}\mu\text{V)} + (\text{Cable Loss (dB)} + \text{Antenna Factor (dB/m)} - \text{AMP(dB)})$$

$$\text{EIRP (dBm)} = E \text{ (dB}\mu\text{V/m)} + 20 \log D - 104.8; \text{ where D is the measurement distance in meters}$$
- 3). Test the EUT in the lowest channel, the middle channel the Highest channel
- 4). The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 5). Repeat above procedures until all frequencies measured was complete

Remark1: Reference test setup 2

Remark2: The emission below 18G were measured at a 3m test distance, while emissions above 18GHz were measured at a 1m test distance. At a measurement distance of 1 meter the limit line was increased by $20 \cdot \log(3/1) = 9.54 \text{ dB}$.

Remark: Reference test setup 2

Remark:

1) The field strength is calculated by adding the Antenna Factor, Cable Factor & AMP. The basic equation with a sample calculation is as follows:

AF = Antenna Factor(dB/m)

Factor = Cable Factor(dB) - Preamplifier (dB)

Level = Reading Level + AF + Factor -95.26

Margin = Limit – Level

2) Scan from 9kHz to 40GHz, The disturbance between 9KHz to 1GHz and 18GHz to 40GHz was very low, and the harmonics were the highest point could be found when testing, so only the harmonics had been displayed. The amplitude of spurious emissions from the radiator which are attenuated more than 20dB below the limit need not be reported.



3) All modes have been tested, but only the worst case data displayed in this report.



3.8 Frequency Stability / Temperature Variation

Measurement Procedure:

Frequency stability testing is performed in accordance with the guidelines of FCC KDB 971168 D01 V03r01; Section 9

. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Specification – The frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block. The frequency stability of the transmitter shall be maintained within $\pm 0.00025\%$ (± 2.5 ppm) of the center frequency.

Time Period and Procedure:

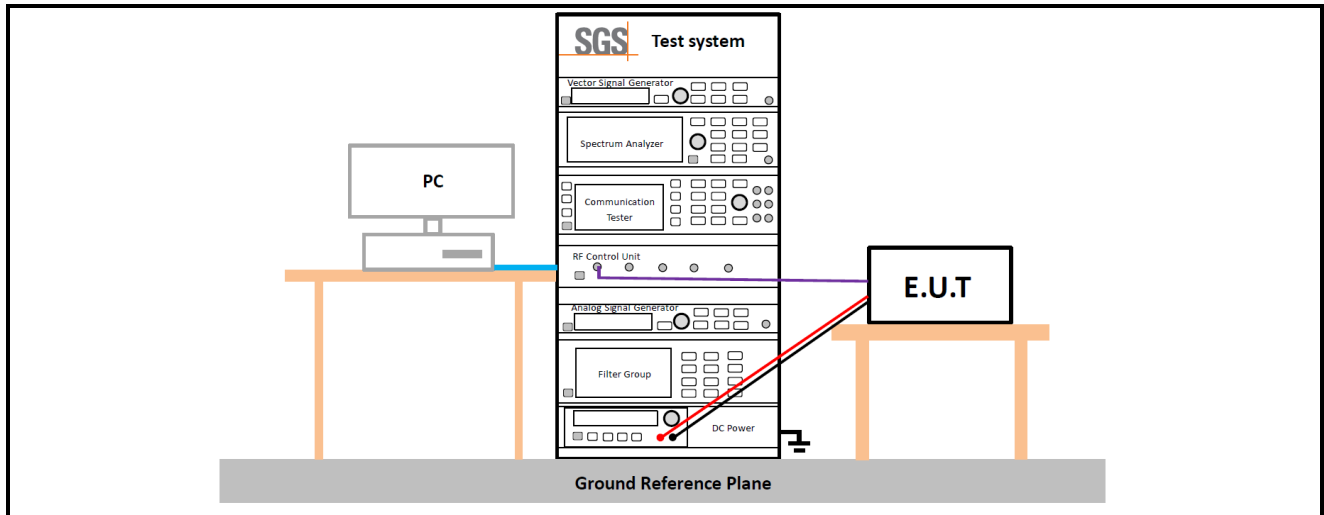
1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
2. The equipment is turned on in a “standby” condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Remark: Reference test setup 3



3.9 Test Setups

3.9.1 Test Setup 1



3.9.2 Test Setup 2

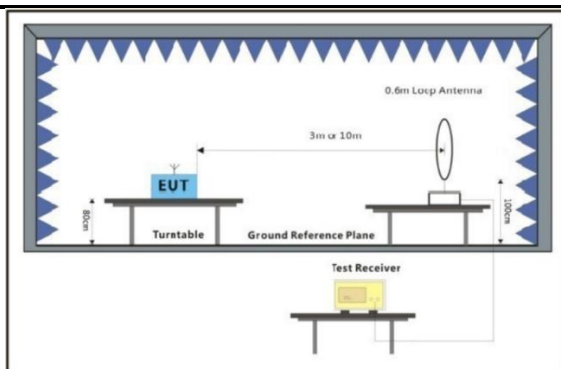


Figure 1. Below 30MHz

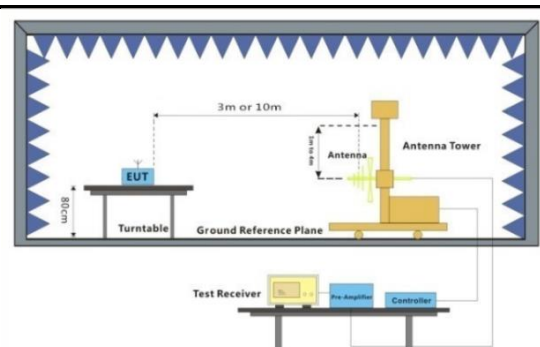


Figure 2. 30MHz to 1GHz

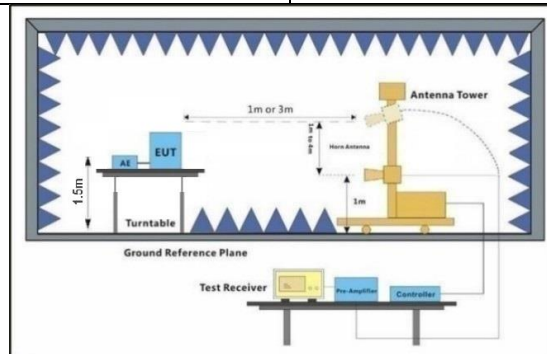
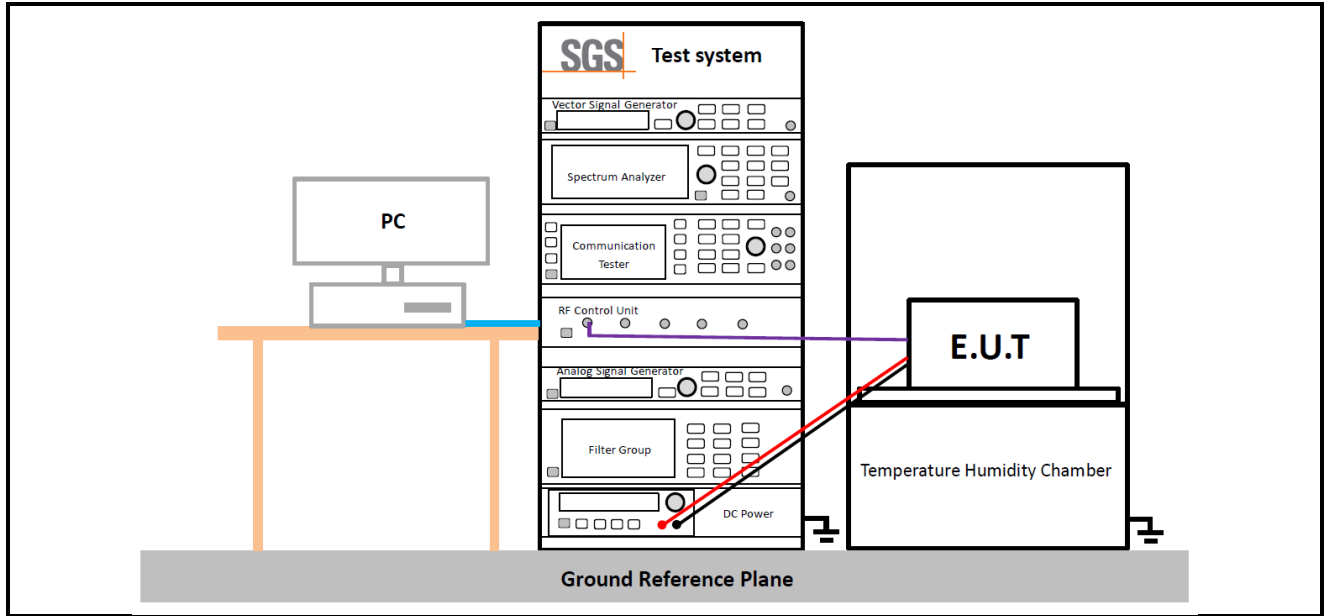


Figure 3. above 1GHz



3.9.3 Test Setup 3



3.10 Test Conditions

Transmit Output Power Data - Average Power, Total	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1;LTE/TM2;LTE/TM3;LTE/TM4
Peak-to-Average Ratio	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1;LTE/TM2;LTE/TM3;LTE/TM4
Bandwidth - Occupied Bandwidth	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1;LTE/TM2;LTE/TM3;LTE/TM4
Bandwidth - Emission Bandwidth	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1;LTE/TM2;LTE/TM3;LTE/TM4
Adjacent Channel Leakage Ratio	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1
Band Edges Compliance	



Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, H (L= low channel, H= high channel)
Test Mode	LTE/TM1
Spurious Emission at Antenna Terminals	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 1
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1
Field Strength of Spurious Radiation	
Test Case	Test Conditions
Test Environment	Ambient Climate & Rated Voltage
Test Setup	Test Setup 2
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)
Test Mode	LTE/TM1 Remark: All bandwidth and modulation of LTE have been pre tested, and only the worst results are reflected in the report.
Frequency Stability	
Test Case	Test Conditions
Test Environment	(1) -30 °C to +50 °C with step 10 °C at Rated Voltage (2) VL, VN and VH of Rated Voltage at Ambient Climate.
Test Setup	Test Setup 3
RF Channels (TX)	M (M= middle channel)
Test Mode	LTE/TM1 The report only show the bandwidth with the worst case.



4 Main Test Instruments

RF conducted test					
Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. date (yyyy/mm/dd)	Cal.Due date (yyyy/mm/dd)
Shielding Room	SAEMC	MSR733	SEM001-09	2022-05-14	2025-05-13
MXA Signal Analyzer	KEYSIGHT	N9020B	SEM004-17	2024-03-20	2025-03-14
Mobile Communications DC Source	Agilent	66319D	SEM011-12	2024-05-06	2025-05-05
Manual Step Attenuator	KEYSIGHT	8494B	SEM021-05	2024-04-06	2025-04-05
Manual Step Attenuator	KEYSIGHT	8496B	SEM021-06	2024-04-06	2025-04-05
Power Sensor	KEYSIGHT	U2021XA	SEM009-15	2024-04-06	2025-04-05
Universal Radio Communication Tester	Rohde & Schwarz	CMW 500	SEM010-03	2024-03-28	2025-03-27
Programmable Temperature & Humidity Chamber	Votsch Industrietechnik GmbH	VT 4002	SEM002-15	2024-04-06	2025-04-05
Coaxial Cable	SGS	N/A	SEM031-01	2024-07-07	2025-07-06

RE in Chamber					
Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. date (yyyy/mm/dd)	Cal.Due date (yyyy/mm/dd)
3m Semi-Anechoic Chamber	AUDIX	N/A	SEM001-02	2022-04-02	2025-04-01
EXA Signal Analyzer (10Hz-44GHz)	Agilent Technologies Inc	N9010A	SEM004-12	2024-04-06	2025-04-05
BiConiLog Antenna (26-3000MHz)	ETS-Lindgren	3142C	SEM003-01	2023-09-17	2025-09-16
Horn Antenna (800MHz-18GHz)	Rohde & Schwarz	HF907	SEM003-07	2022-07-24	2024-07-23
				2024-07-22	2026-07-21
Horn Antenna (15-40GHz)	Schwarzbeck	BBHA 9170	SEM003-15	2022-08-10	2024-08-09
				2024-08-08	2026-08-07
Broad-Band Horn Antenna	Schwarzbeck	BBHA 9120D	SEM003-32	2021-09-26	2024-09-25
Amplifier (0.1-1300MHz)	HP	8447D	SEM005-02	2023-09-15	2024-09-14



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SZEMC-TRF-01 Rev. A/1

Report No.: SZCR240700252202

Page: 26 of 28

Microwave System Amplifier(0.5-26.5GHz)	Agilent	83017A	SEM005-25	2023-09-21	2024-09-20
Pre-amplifier (26-40GHz)	Compliance Directions Systems Inc.	PAP-2640-50	SEM005-08	2024-03-21	2025-03-20
Substitution Antenna	Schwarzbeck	VULB9168	SEM003-18	2022-08-07	2025-08-06
Substitution Antenna	Rohde&Schwarz	HF907	SEM003-06	2022-08-07	2024-08-06
				2024-08-05	2026-08-04
Signal Generator(9kHz-40GHz)	N5173B	MY53270267	Agilent	2023-07-11	2024-07-10
				2024-07-09	2025-07-08
Measurement Software	AUDIX	e3 V8.2014-6-27	N/A	N/A	N/A
Coaxial Cable	SGS	N/A	SEM026-06	2023-07-07	2024-07-06
				2024-07-05	2025-07-04

General used equipment					
Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. date (yyyy/mm/dd)	Cal.Due date (yyyy/mm/dd)
Humidity/ Temperature Indicator	Mingle	N/A	SEM002-08	2023-09-04	2024-09-03
				2024-09-02	2025-09-01
Humidity/ Temperature Indicator	Anymetre	TH101B	SEM002-09	2023-09-04	2024-09-03
				2024-09-02	2025-09-01
Barometer	Changchun Meteorological Industry Factory	DYM3	SEM002-01	2024-03-20	2025-03-19



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5 Measurement Uncertainty

For a 95% confidence level ($k = 2$), the measurement expanded uncertainties for defined systems, in accordance with the recommendations of ISO 17025 as following:

No.	Item	Measurement Uncertainty
1	Radio Frequency	$\pm 5.4 \times 10^{-8}$
2	Duty cycle	$\pm 0.3\%$
3	Occupied Bandwidth	$\pm 3\%$
4	RF conducted power	$\pm 0.8\text{dB}$
5	RF power density	$\pm 0.4\text{dB}$
6	Conducted Spurious emissions	$\pm 2.7\text{dB}$
7	Radiated Spurious emission test	$\pm 3.1\text{dB}$ (Below 1GHz) $\pm 4.4\text{dB}$ (Above 1GHz)
8	Temperature test	$\pm 1^\circ\text{C}$
9	Humidity test	$\pm 3\%$
10	Supply voltages	$\pm 1.5\%$
11	Time	$\pm 3\%$

Remark:

The U_{lab} (lab Uncertainty) is less than $U_{\text{CISPR/ETSI}}$ (CISPR/ETSI Uncertainty), so the test results
 – compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;
 – non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.



6 Appendixes

Appendix A.1	WWAN Setup Photos
Appendix B.1	LTE Band 48
Appendix B.2	LTE Band CA_48C

---End of Report---

